

PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of:

PAGE et al

International Appln. No.: PCT/GB2003/004750

Filed: Concurrently herewith Attorney Dkt. No.: 42981.00009

For: CHARGED PARTICLE SPECTROMETER AND DETECTOR THEREFOR

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450
Attention: PCT DO/EO/US

May 3, 2005

Sir:

This is an Information Disclosure Statement submitted under 37 C.F.R.1.97(b).

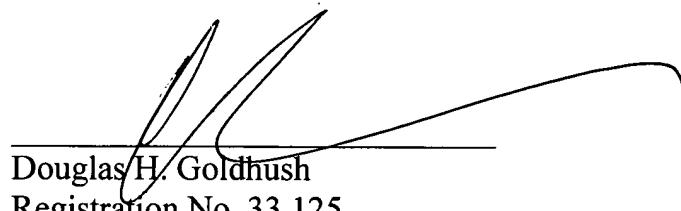
The references cited in the attached Form PTO-1449 were cited in the enclosed International Search Report issued by the European Patent Office in connection with the above international application. It is understood that the European Patent Office has sent a copy of each of the cited references to the U.S. Patent and Trademark Office. If this is not the case, please contact Applicants' representative at the telephone number listed below. Also enclosed is a UK Search Report and a copy of each reference cited therein.

In view of the above, all requirements of 37 CFR 1.97 and all official guidelines pertaining to Information Disclosure Statements have been complied with, and it is

therefore respectfully requested that the Examiner consider the references and make them of record in this application.

In the event that there are any fees due with respect to the filing of this paper, please charge Counsel's Deposit Account No. 50-2222.

Respectfully submitted,



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Enclosures: PTO-1449 Form
International Search Report
UK Search Report
2 References

FORM PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. 42981.00009	SERIAL NO. 107533570 New Application
LIST OF REFERENCES CITED BY APPLICANT <i>(Use several sheets if necessary)</i>		APPLICANT PAGE et al	
		FILING DATE May 3, 2005	GROUP Not yet assigned

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB-CLASS	FILING DATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION YES NO PART.
	AG	EP 1 170 778 A	01/09/2002	European			
	AH	GB 2 359 187 A	08/15/2001	United Kingdom		xx	
	AI						
	AJ						
	AK						

OTHER REFERENCES (*Including Author, Title, Date, Pertinent Pages, Etc.*)

AL	Hatfield et al, "An integrated multichannel charged-particle sensing system", Sensors and Actuators, Vol. 54, no. 1-3, June 1, 1996, pages 777-781, XP004077965.
AM	High Performance Imaging XPS - The Spherical Mirror Analyser available at http://www.kratos.com/Agen/SMA.html , last updated October 4, 1998.
AN	
EXAMINER	DATE CONSIDERED

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.